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Sommario/riassunto	ETS15 is dedicated to presenting and discussing results, applications, emerging ideas and trends in the following topics Analog Test ATE Hardware and Software Board Test and Diagnosis Boundary Scan, BIST and Self Repair Current Based and Defect Based Test Delay and Performance Test Dependability and Functional Safety DfT Design for Manufacturing Diagnosis and Silicon Debug Economics of Test Emerging Technologies Failure Analysis Fault Modeling and Simulation Fault Tolerance GPU Test High Speed I O Test Low Power IC Test Memory Test and Repair MEMS Test Microprocessor Test Mixed Signal Test Multi Many core Processor Test Nanotechnology Test On line Test Power Issues in Test Reconfigurable System Test RF Test Security and Trust Issues in Test Sensor Test Signal Integrity Test SIP, Stacked, 3D IC Test SoC Test Soft Errors Standards in Test System Test Test compression Test Quality & Synthesis Thermal Issues in Test Validation and Verification Variability Issues in Test Yield Analysis.